

1. Features

The KIA5610 is the highest performance trench N-ch MOSFETS with extreme high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The KIA5610 meet the RoHS and green product requirement, 100% EAS guaranteed with full function reliability approved.

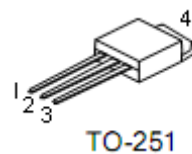
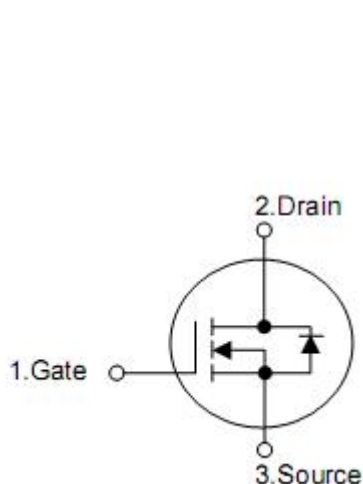
2. Features

- n $R_{DS(ON)}=310m\Omega@V_{GS}=10V$
- n Advanced high cell density trench technology
- n Super low gate charge
- n Excellent Cdv/dt effect desline
- n Green device available

3. Applications

- n High frequency point-of-load synchronous buck converter
- n Networking DC-DC power system
- n Load switch

4.Symbol



| Pin | Function |
|-----|----------|
| 1 | Gate |
| 2 | Drain |
| 3 | Source |

4. Absolute maximum ratings

| Parameter | Symbol | Rating | Units | |
|--|----------------|-------------------|------------|------|
| Drain-source voltage | V_{DSS} | 100 | V | |
| Gate-source voltage | V_{GS} | ± 20 | V | |
| Continuous drain current , $V_{GS}@10V$ ¹ | I_D | $T_C=25^\circ C$ | 5.4 | |
| | | $T_C=100^\circ C$ | 3.4 | |
| | | $T_A=25^\circ C$ | 1.7 | |
| | | $T_A=100^\circ C$ | 1.3 | |
| Pulsed drain current ² | I_{DM} | 11 | A | |
| Power dissipation ³ | P_D | $T_C=25^\circ C$ | | 20.8 |
| | | $T_A=25^\circ C$ | | 2 |
| Operating junction and storage temperature range | T_J, T_{STG} | -55 to 150 | $^\circ C$ | |

5. Thermal characteristics

| Parameter | Symbol | Typ | Max | Unit |
|-------------------------------------|-----------------|-----|-----|--------------|
| Thermal resistance junction-case | $R_{\theta JC}$ | - | 6 | $^\circ C/W$ |
| Thermal resistance junction-ambient | $R_{\theta JA}$ | - | 62 | |

6. Electrical characteristics

($T_J=25^{\circ}\text{C}$, unless otherwise noted)

| Parameter | Symbol | Test Conditions | Min | Typ | Max | Units |
|--|------------------------------|--|-----|--------|-----------|-----------------------|
| Drain-source breakdown voltage | BV_{DSS} | $V_{GS}=0V, I_D=250\mu A$ | 100 | - | - | V |
| BV_{DSS} temperature coefficient | $\Delta BV_{DSS}/\Delta T_J$ | Reference 25°C $I_D=1mA$ | - | 0.0672 | - | $V/^{\circ}\text{C}$ |
| Drain-source on-resistance ² | $R_{DS(on)}$ | $V_{GS}=10V, I_D=5A$ | - | - | 310 | m Ω |
| | | $V_{GS}=4.5V, I_D=3A$ | - | - | 320 | |
| Gate threshold voltage | $V_{GS(TH)}$ | $V_{DS}=V_{GS}, I_D=250\mu A$ | 1.0 | - | 2.5 | V |
| $V_{GS(TH)}$ temperature coefficient | $\Delta V_{GS(TH)}$ | | - | -4.12 | - | $mV/^{\circ}\text{C}$ |
| Drain-source leakage current | I_{DSS} | $V_{DS}=80V, V_{GS}=0V$ $T_J=25^{\circ}\text{C}$ | - | - | 1 | μA |
| | | $V_{DS}=80V, V_{GS}=0V$ $T_J=55^{\circ}\text{C}$ | - | - | 5 | |
| Gate-source forward leakage | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | - | - | ± 100 | nA |
| Forward transconductance | g_{fs} | $V_{DS}=5V, I_D=3A$ | - | 5.4 | - | S |
| Gate resistance | R_g | $V_{DS}=0V, V_{GS}=0V$ $f=1MHz$ | - | 2.5 | - | Ω |
| Total gate charge(10V) | Q_g | $V_{DS}=80V, I_D=5A$ $V_{GS}=10V$ | - | 9.6 | - | nC |
| Gate-source charge | Q_{gs} | | - | 1.83 | - | |
| Gate-drain charge | Q_{gd} | | - | 1.85 | - | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD}=50V, I_D=5A,$ $R_G=3.3\Omega, V_{GS}=10V$ | - | 1.4 | - | ns |
| Rise time | t_r | | - | 30.6 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 11.2 | - | |
| Fall time | t_f | | - | 6 | - | |
| Input capacitance | C_{iss} | $V_{DS}=15V, V_{GS}=0V$ $f=1MHz$ | - | 508 | - | pF |
| Output capacitance | C_{oss} | | - | 29 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 16.4 | - | |
| Continuous source current ^{1,6} | I_S | $V_D=V_G=0V,$ Force current | - | - | 5.4 | A |
| Maximum pulsed current ^{2,6} | I_{SM} | | - | - | 11 | |
| Diode forward voltage ² | V_{SD} | $I_S=1A, V_{GS}=0V$ $T_J=25^{\circ}\text{C}$ | - | - | 1.2 | V |
| Reverse recovery time | t_{rr} | $I_F=5A, di/dt=100A/\mu s$ $T_J=25^{\circ}\text{C}$ | - | 20 | - | ns |
| Reverse recovery charge | Q_{rr} | | - | 19 | - | nC |

Note:

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
2. The data tested by pulsed, pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
3. The power dissipation is limited by 150°C junction temperature.
4. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

7. Typical operating characteristics

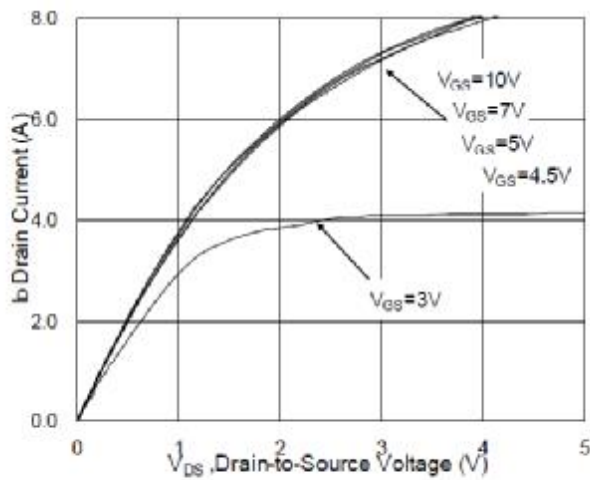


Fig.1 typical output characteristics

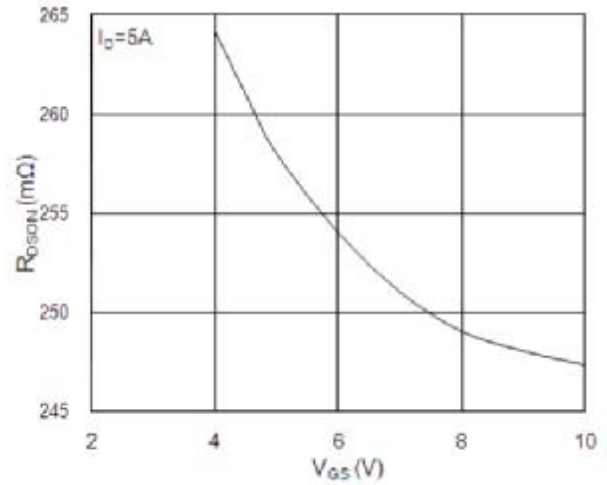


Fig.2 on-resistance vs. Gate-Source

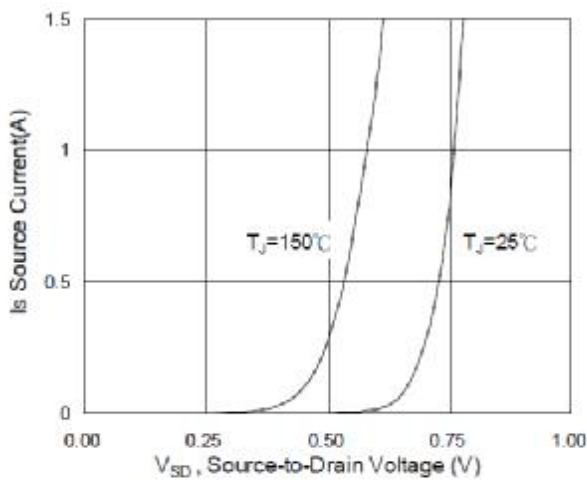


Fig.3 forward characteristic of reverse

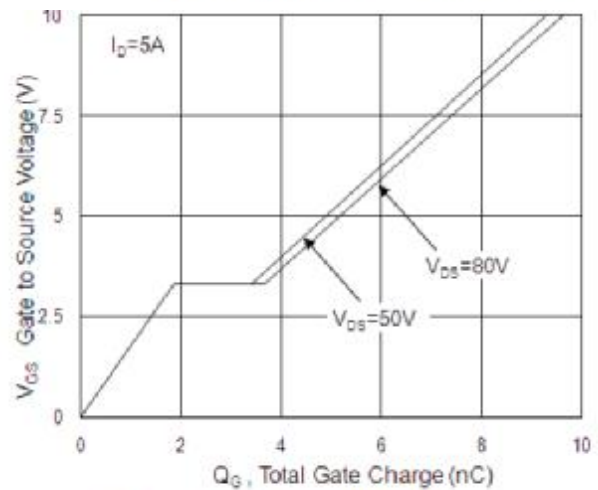


Fig.4 gate-charge characteristics

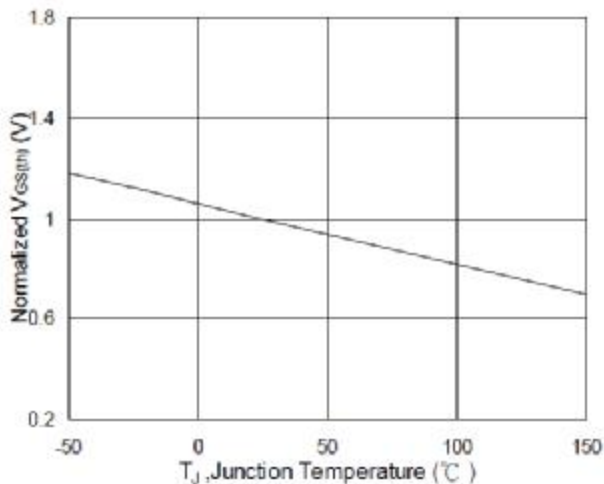


Fig.5 normalized Vgs(th) vs TJ

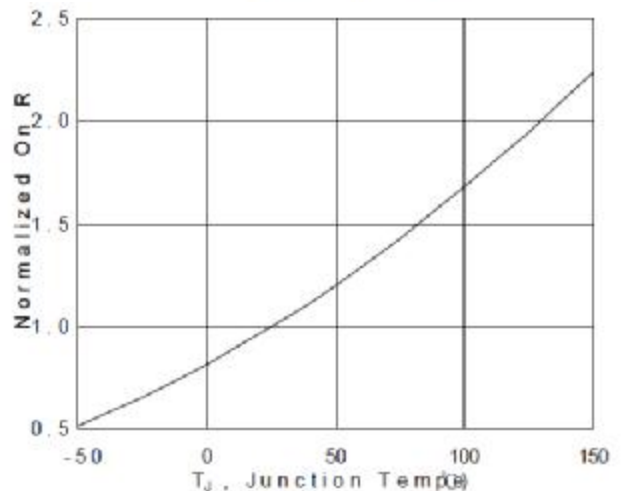


Fig.6 normalized Rds(on) vs TJ

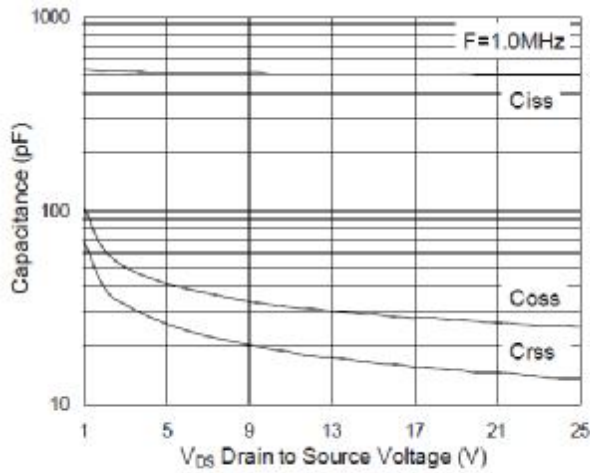


Fig.7 Capacitance

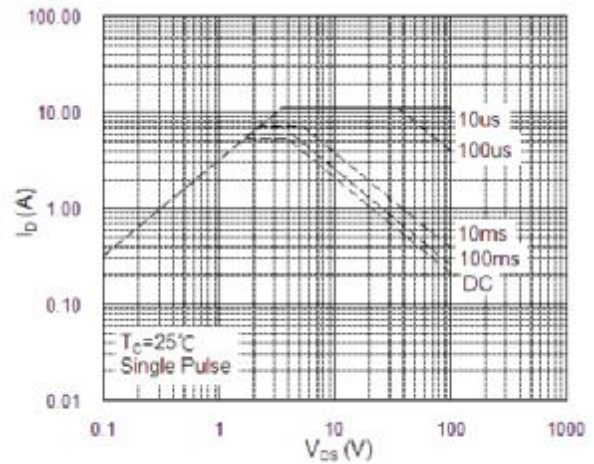


Fig.8 Safe operating area

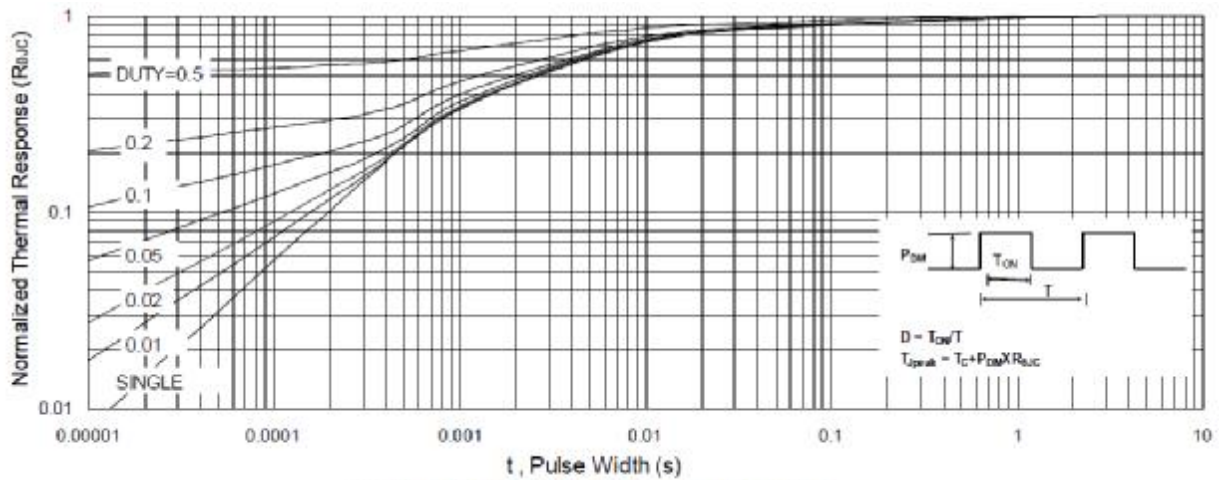


Fig.9 Normalized maximum transient thermal impedance

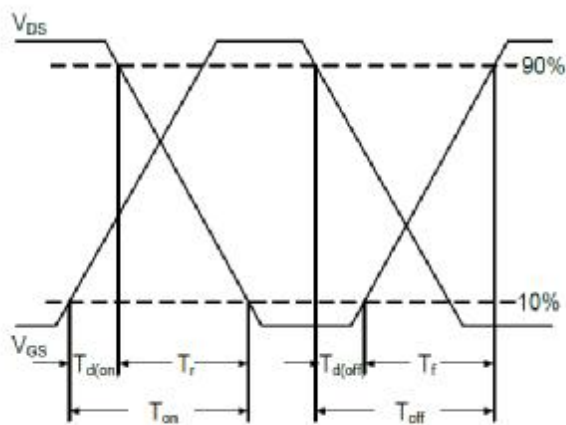


Fig.10 Switching time waveform

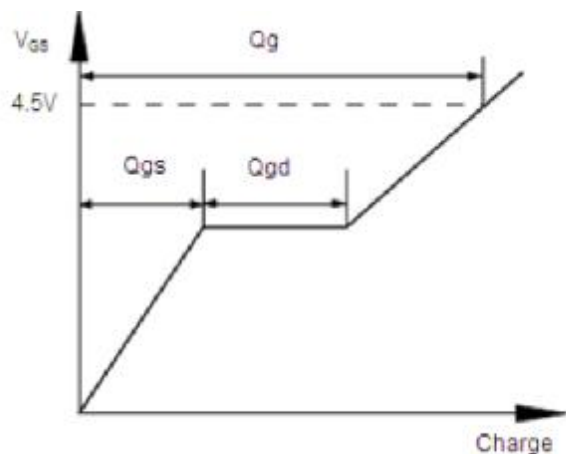


Fig.11 Gate charge waveform